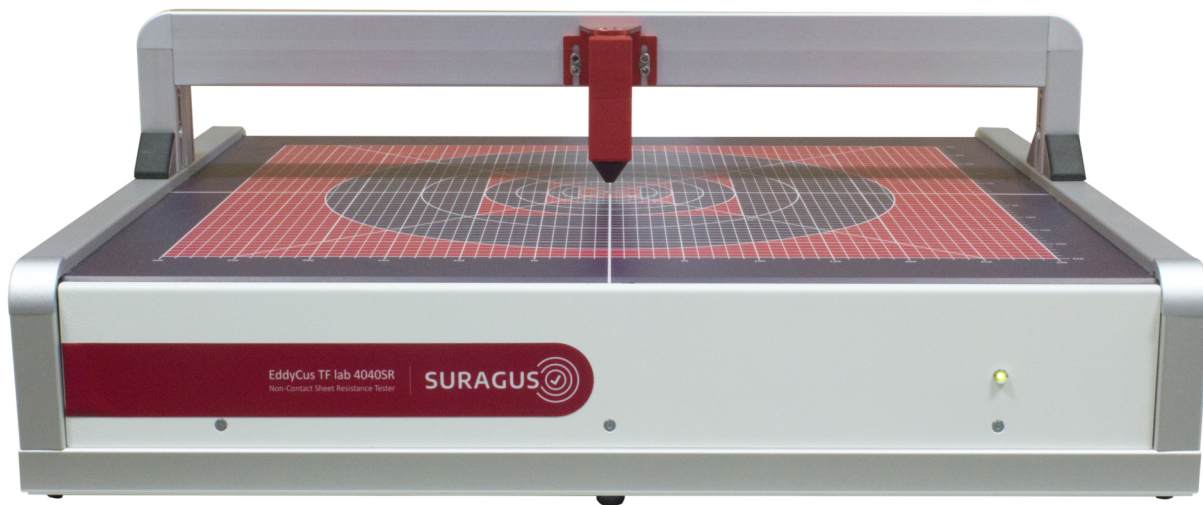


EddyCus® TF lab 4040MT – Metal Thickness Tester

P_T_4040MT_21



Highlights

- ▶ Contact-free and realtime
- ▶ Accurate single-point measurement
- ▶ Manual mapping guided by easy-to-handle software
- ▶ Measurement of encapsulated layers
- ▶ Characterization of multilayer materials upon request

Device Series

- ▶ Metal thickness (nm, μm)
- ▶ Sheet resistance (Ohm/sq)
- ▶ Emissivity
- ▶ Conductivity / resistivity (mOhm cm)
- ▶ Electrical anisotropy (%)
- ▶ Weight (g/m^2) and drying status (%)
- ▶ Permeability (H/m) Beta
- ▶ Transmittance, reflectance, haze

SURAGUS GmbH
Maria-Reiche-Strasse 1
01109 Dresden
Germany

上海昊量光电设备有限公司

中国区代理

官网: www.auniontech.com 电话: 021-34241961
邮箱: info@ahuniontech.com
地址: 上海市徐汇区虹梅路2007号远中产业园三期6号楼3楼

Applications

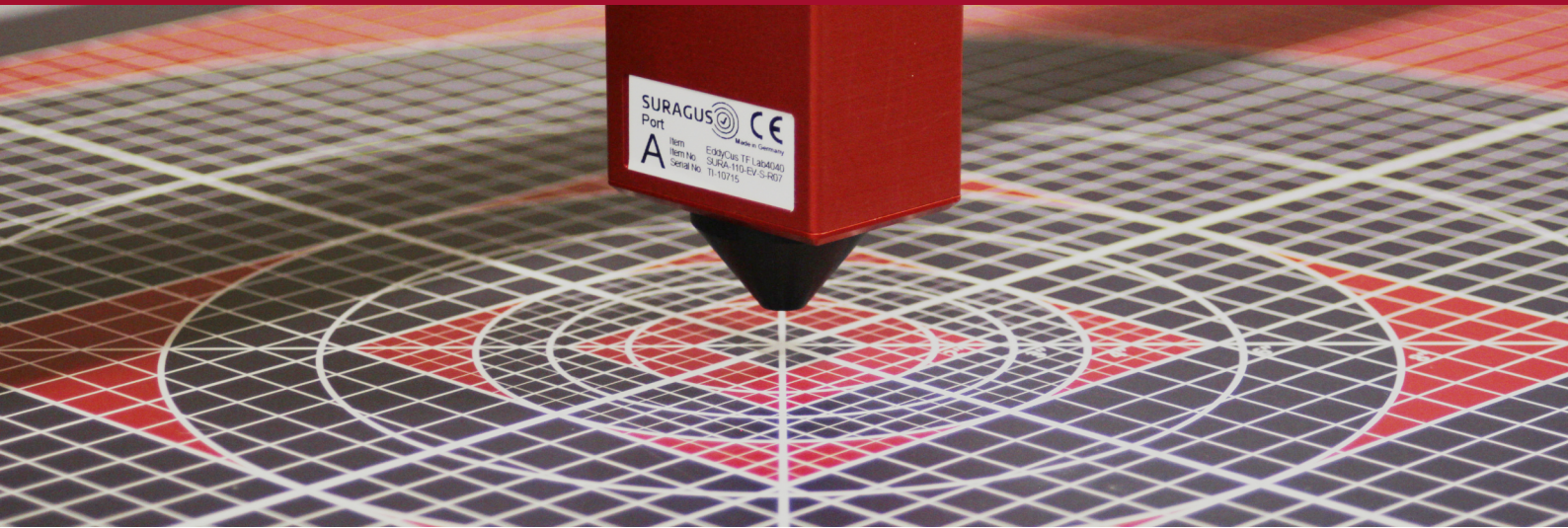
- ▶ Semiconductor industry
- ▶ Electronic industry
- ▶ Metallization in photovoltaics
- ▶ Batteries, fuel cells, capacitors
- ▶ Boards and panels (PCB, WLP, PLP)
- ▶ Mirrors and lenses
- ▶ Barrier films
- ▶ EMC/EMI Shielding
- ▶ Heating and de-icing films
- ▶ Medical applications

Materials

- ▶ Metal films
- ▶ Metal meshes
- ▶ Metal substrates
- ▶ Alloy films
- ▶ Alloy substrates

Engineered and Made in Germany 





Measurement technology	Non-contact eddy current sensor
Substrates	Foil, glass, wafer, etc.
Substrate area	29.5" x 25.6" / 750 mm x 650 mm (for 400 mm x 400 mm samples)
Max. sample thickness/ sensor gap	3 / 5 / 10 / 25 mm (defined by the thickest sample)
Metal thickness range	Low 1 – 10 nm; 2 – 5 % accuracy
Accuracies depend on the selected setup and the type / conductivity of the metal (e.g. copper, aluminum, silver)	Standard 10 – 1,000 nm; 1 – 3 % accuracy
	High 1 – 100 μm; 0.5 – 3 % accuracy
Metal thickness calibration	Direct thickness calibration / sheet resistance conversion
Device dimensions (w/h/d) / weight	30" x 12" x 26" / 760 mm x 310 mm x 660 mm / 20 kg
Further available features / other tool configurations	Sheet resistance measurement / conductivity / resistivity / emissivity / permeability (<i>beta</i>) / electrical anisotropy / optical transmittance / optical reflectance / haze

Device Control and Software